

CLEANLINESS ANALYSIS SOLUTIONS

Target contamination fast



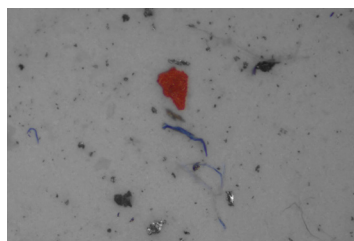
Technical cleanliness plays a central role in quality control. It determines performance, lifetime, and overall product quality for various industries. Examples include automotive parts and electronic components, lubricants, hydraulic fluids, oils, and pharmaceutical products. Reliable and efficient cleanliness analysis is necessary to ensure quality.

Efficient and reliable cleanliness analysis solutions from Leica Microsystems enable suppliers and manufacturers to ensure better product performance and lifetime through the analysis of particle quantity, size, and composition.

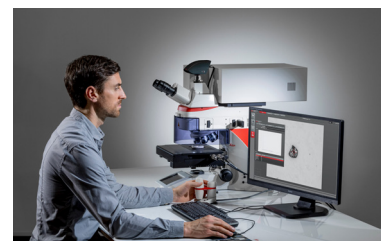
Your benefits with Leica cleanliness analysis solutions



Fast-forward to your results
Increase throughput by analyzing more in less time.



Get more insights on particles
Obtain more insights on the source of particles for better risk assessment and more confident decisions.



Work flexibly today and in the future
Meet all your current needs and be prepared for changing requirements.

The right cleanliness analysis solution for your needs

Perform more efficient and reliable particle counting and classification according to international and regional standards with a selection of dedicated configurations tailored to meet your specific requirements.



Standard:	Advanced:	Professional:
Emspira 3 digital microscope with Cleanliness Expert analysis software	DM6 M microscope, K3 camera, and Cleanliness Expert analysis software	DM6 M microscope with LIBS, K3 camera, and Cleanliness Expert analysis software
Particle sizes down to 25 µm	Particle sizes down to 5 µm	Particle sizes down to 5 µm
Manual differentiation of metallic and non-metallic particles	Fully automated recognition of metallic and non-metallic particles and between particles and fibers	Fully automated recognition of metallic and non-metallic particles and between particles and fibers
Measurement of particles in X and Y	Measurement of particles in X, Y, and Z	Measurement of particles in X, Y, and Z
		Simultaneous particle composition identification
		No sample transfer or additional sample preparation

CONNECT WITH US!

